

Certificate of Analysis

| Test | Specification | Result |
|---|---------------|-------------|
| Assay ((CH ₃) ₂ CO) (by GC, corrected for water) | ≥ 99.5 % | 99.8 % |
| Color (APHA) | ≤ 10 | < 5 |
| Residue after Evaporation | ≤ 5 ppm | < 1 ppm |
| Titration Acid (µeq/g) | ≤ 0.3 | 0.2 |
| Titration Base (µeq/g) | ≤ 0.5 | 0.1 |
| Water (H ₂ O) | ≤ 0.5 % | 0.2 % |
| Solubility in H ₂ O | Passes Test | Passes Test |
| Chloride (Cl) | ≤ 0.2 ppm | < 0.1 ppm |
| Phosphate (PO ₄) | ≤ 0.05 ppm | < 0.05 ppm |
| Trace Impurities - Aluminum (Al) | ≤ 50.0 ppb | < 5.0 ppb |
| Arsenic and Antimony (as As) | ≤ 5.0 ppb | < 5.0 ppb |
| Trace Impurities - Barium (Ba) | ≤ 20.0 ppb | < 1.0 ppb |
| Trace Impurities - Beryllium (Be) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Bismuth (Bi) | ≤ 20.0 ppb | < 10.0 ppb |
| Trace Impurities - Boron (B) | ≤ 10.0 ppb | < 5.0 ppb |
| Trace Impurities - Cadmium (Cd) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Calcium (Ca) | ≤ 25.0 ppb | 1.6 ppb |
| Trace Impurities - Chromium (Cr) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Cobalt (Co) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Copper (Cu) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Gallium (Ga) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Germanium (Ge) | ≤ 10.0 ppb | < 10.0 ppb |
| Trace Impurities - Gold (Au) | ≤ 20 ppb | < 5 ppb |
| Trace Impurities - Iron (Fe) | ≤ 20.0 ppb | < 1.0 ppb |
| Trace Impurities - Lead (Pb) | ≤ 10.0 ppb | < 10.0 ppb |
| Trace Impurities - Lithium (Li) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities - Magnesium (Mg) | ≤ 20 ppb | < 1 ppb |
| Trace Impurities - Manganese (Mn) | ≤ 10.0 ppb | < 1.0 ppb |

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| Test | Specification | Result |
|---|---------------|------------|
| Trace Impurities – Molybdenum (Mo) | ≤ 10.0 ppb | < 5.0 ppb |
| Trace Impurities – Nickel (Ni) | ≤ 10.0 ppb | < 5.0 ppb |
| Trace Impurities – Niobium (Nb) | ≤ 50.0 ppb | < 1.0 ppb |
| Trace Impurities – Potassium (K) | ≤ 10.0 ppb | < 10.0 ppb |
| Trace Impurities – Silicon (Si) | ≤ 50 ppb | < 10 ppb |
| Trace Impurities – Silver (Ag) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities – Sodium (Na) | ≤ 10.0 ppb | < 5.0 ppb |
| Trace Impurities – Strontium (Sr) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities – Tantalum (Ta) | ≤ 50.0 ppb | < 5.0 ppb |
| Trace Impurities – Thallium (Tl) | ≤ 10.0 ppb | < 5.0 ppb |
| Trace Impurities – Tin (Sn) | ≤ 20.0 ppb | < 10.0 ppb |
| Trace Impurities – Titanium (Ti) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities – Vanadium (V) | ≤ 10.0 ppb | < 1.0 ppb |
| Trace Impurities – Zinc (Zn) | ≤ 20.0 ppb | < 1.0 ppb |
| Trace Impurities – Zirconium (Zr) | ≤ 10.0 ppb | < 1.0 ppb |
| Particle Count – 0.5 µm and greater (Rion KS42AF) | ≤ 100 par/ml | 4 par/ml |
| Particle Count – 1.0 µm and greater (Rion KS42AF) | ≤ 8 par/ml | 2 par/ml |

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Acetone
CMOS



Material No.: 9005-68
Batch No.: 22K2261015

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|------|---------------|--------|
|------|---------------|--------|

For Microelectronic Use

Country of Origin: USA
Packaging Site: Paris Mfg Ctr & DC



Jamie Ethier
Vice President Global Quality

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700
Avantor Performance Materials, LLC
100 Matsonford Rd, Suite 200, Radnor, PA 19087. U.S.A. Phone 610.386.1700